



IEEE802.3 4P Task Force Channel Pair To Pair Resistance Imbalance

**Investigation of a low resistance
connector / Rev.2**

IEC 60603-7 (Ed.3)- Summary of specifications

- › **Input to output d.c. resistance (6.4.5):**
Mated connectors
200mΩ maximum
- › **Initial contact resistance (6.4.4):**
Contact interface only
20mΩ maximum
- › **Input to output d.c.resistance unbalance (6.4.6):**
Mated connectors, max. difference between max. and min. (from 6.4.5)
50mΩ maximum
- › **Environmental or mechanical “aging”:**
20mΩ maximum Contact resistance change from initial

IEC 60603-7

- For the worst case model of the Ad-hoc, (minimum resistance, maximum unbalance) the maximum values according 60603-7 ($200m\Omega$ / $50m\Omega$) *are probably too high/not relevant.*

But also a low resistance connector is affected by aging (environmental stress, mechanical operation,..) which would increase the initial resistance unbalance over lifetime.

- To increase the database for the Ad-hoc model, this document lists the resistance test data of a specific low resistance RJ-45.

Resistance measurements on samples

- **Product:**
Short Top Entry
RJ-45 connector with low
input to output resistance.



- **Testing and test references**
according IEC 60603-7:
Jack mounted on PCB, mated connections
measured with standard RJ-45 plug (short
cable terminations)



Results (Initial):

› Input to output d.c. resistance 6.4.5 (initial)

Mated connectors, cable termination (plug) to mounting PCB (jack).

22 samples @8 contacts:

23.34 mΩ Max

20.19 mΩ Mean

17.84 mΩ Min)

› Resistance unbalance 6.4.6 (inital):

Mated connectors, difference between min. and max.

5.2 mΩ maximum unbalance

› Initial Contact Resistance 6.4.4

(without bulk resistance of connection)

11.1 / 7.9 / 6.9 (mΩ Max/Mean/Min)

Results (Aging)

Changes from initial resistance:

- › **AP**-Thermal Stress / Cyclic damp heat (8 samples):
3.1 / 1.3 / -0.9 (mΩ Max/Mean/Min)
- › **BP**-Flowing Mix Gas/Corrosion and mechanical operation (8 samples):
 - a) 1250cycles (1st half) + FMG corrosion (BP4):
8.0 / 0.4 / -1.4 (mΩ Max/Mean/Min)
 - b) further 1250 cycles mech. operation (BP6)
4.0 / 1.0 / -0.9 (mΩ Max/Mean/Min)
- › **CP**-Vibration (10 samples)
0.3 / -0.4 / -1.3 (mΩ Max/Mean/Min)
- › **DP**-Electrical load and temperature (6 samples)
3.1 / 0.0 / -3.4 (mΩ Max/Mean/Min)

Summary of testing

- The influence of aging (corrosion, mechanical operation, load+temp.) to the initial resistance of a connection is higher than the initial resistance unbalance between contacts (*).
- Aging can increase or reduce contact resistance

(*) It has to be considered that the investigated jack has NiPd plating which offers a high contact reliability.

A similar jack with a low quality plating could show a higher change of the contact resistance after aging.

This result is for a specific jack. A more complex jack (fully Cat6_A) could have a higher initial resistance unbalance but probably also a higher resistance in general.

Summary of testing

› d.c. Resistance of connection (plug and jack) 22 samples:

- Minimum 17.84 mΩ initial only
- Minimum 17.53 mΩ with aging
- Maximum 23.34 mΩ initial only
- Maximum 29.47 mΩ with aging

› Resistance unbalance (from above)

- Maximum 5.2 mΩ initial only
- Maximum 11.94 mΩ with aging